

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MIWA ET AL.	
		Examiner YUBIN HUNG	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,393,148	05-2002	Bhaskar, Ranjit	382/169
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
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I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Sharon et al. ("Segmentation and boundary detection using multiscale intensity measurements", IEEE Proc. on 2001 CVPR, Vol. 1, pp. 469-476)
V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.